

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 13909-118001	Application No. 10/625,897
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 1.98(b))		Applicant von Bergen et al. Filing Date July 24, 2003 Group Art Unit 2186 2167			

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
MB	AA	US-4849905	07-1989	Loeb et al.			
MB	AB	US-5355473	10-1994	Au			
MB	AC	US-5557786	09-1996	Johnson, Jr.			
MB	AD	US-5737732	04-1998	Gibson et al.			

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No
MB	AE	0 657 830 A1	06-1995	EPO			

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
MB	AF	Date, C.J., "Introduction to Database Systems, Vol. 1," 1990, Addison Wesley, Reading, MA, USA, paragraph '03.6!, figs. 3.17 and 3.18
MB	AG	Haerder, Theo and Erhard Rahm, "Datenbanksysteme," 1999, Springer, Heidelberg, pp. 207-210, 227-233, figs. 7.15, 8.1 and 8.2.B, English translation provided, 10 pgs.
	AH	
	AI	

Examiner Signature <i>Malte Loeb</i>	Date Considered <i>6/4/05</i>
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U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
MB	AA	US-2002/0032676 A1	03/14/2002	Wheat et al.			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
MB	AB	WO 02/061612 A	08/08/2002	WIPO				
MB	AC	WO 02/061613 A	08/08/2002	WIPO				

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Examiner Signature

Matthew Bradley

Date Considered

10/11/05

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